

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/623,226	CHAI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,549,083 A	10-1985	Ozawa, Lyuji	250/458.1
*	B	US-4,664,744 A	05-1987	Le Gal et al.	117/3
*	C	US-4,928,017 A	05-1990	Kemmler-Sack et al.	250/483.1
*	D	US-4,958,080 A	09-1990	Melcher, Charles L.	250/483.1
*	E	US-5,003,181 A	03-1991	Morlotti, Romano	250/484.4
*	F	US-5,025,151 A	06-1991	Melcher, Charles L.	250/269.6
*	G	US-5,610,967 A	03-1997	Moorman et al.	378/154
*	H	US-5,644,612 A	07-1997	Moorman et al.	378/98.2
*	I	US-5,651,047 A	07-1997	Moorman et al.	378/98.8
*	J	US-5,660,627 A	08-1997	Manente et al.	117/12
*	K	US-5,729,584 A	03-1998	Moorman et al.	378/146
*	L	US-5,751,785 A	05-1998	Moorman et al.	378/146
*	M	US-5,835,561 A	11-1998	Moorman et al.	378/98

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	DE 2234968	01-1973	DE	Watanabe et al	-
*	O	GB 1336518	11-1973	GB	Watanabe et al	-
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	IEEE Transactions on Nuclear Science, vol. 36, No. 1, Feb. 1989, Ishibashi, et al. "Cerium Doped GSO Scintillators and its Application to Position Sensitive Detectors" pp. 170-172.
*	V	IEEE Transactions on Nuclear Science, vol. 40, No. 4, Aug. 1993, Daghigian, et al. "Evaluation of Cerium Doped Lutetium Oxyorthosilicate (LSO) Scintillation Crystal for PET" pp. 1045-1047.
*	W	IEEE Transactions on Nuclear Science, vol. 43, No. 3, Jun. 1996, Novotny, et al. "A Plastic-BaF <sub>2</sub> Phoswich Telescope for Charged/Neutral Particle and Photon Detection" pp 1260-1266.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,859,893 A	01-1999	Moorman et al.	378/154
*	B	US-6,323,489 B1	11-2001	McClellan, Kenneth J.	250/361R
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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	R					
	S					
	T					

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